Supplementary Materials

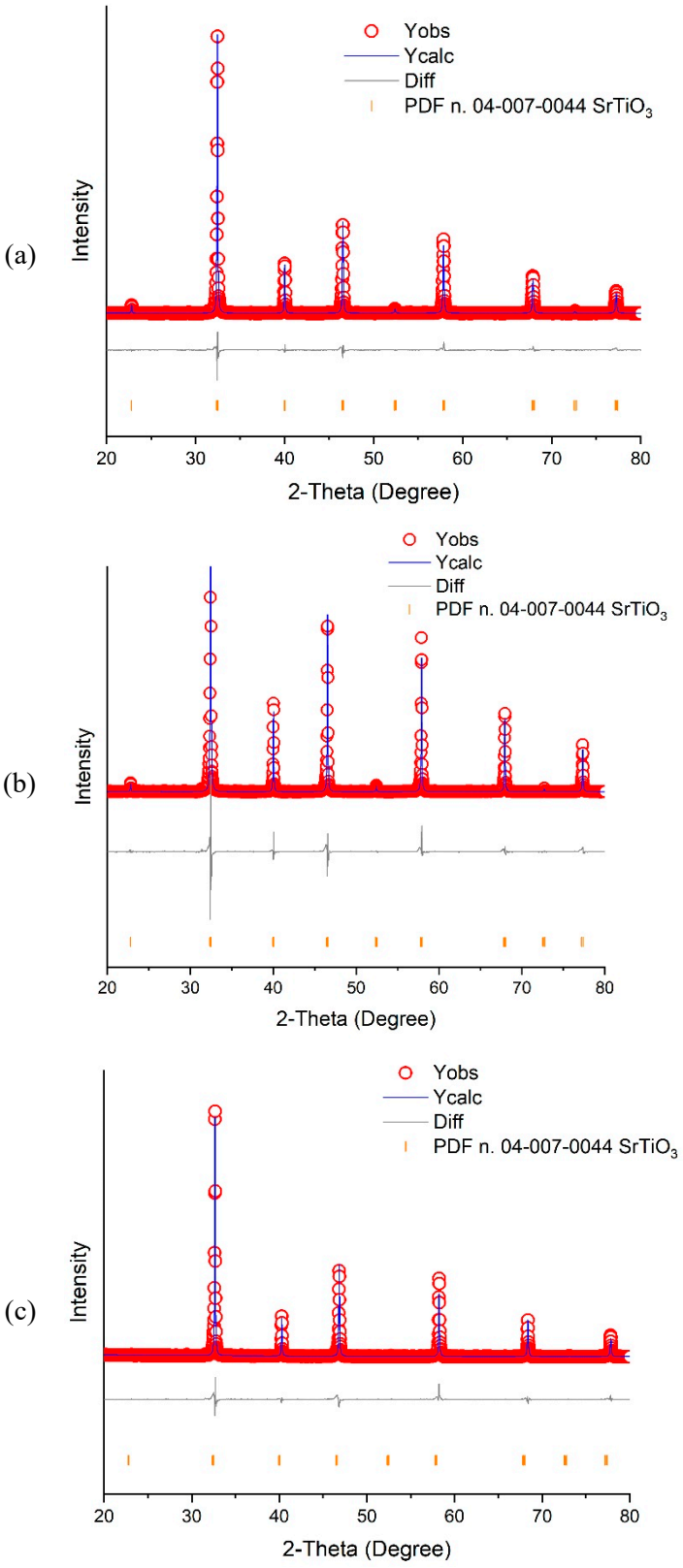

Figure S1 Rietveld refinement of X-ray diffraction (XRD) patterns recorded on sintered membranes composed by (a) STF82, (b) SCTF1982, and (c) SCTF6482.